Amendments to the Specification

Please replace the paragraph beginning on page 21, line 14, with the following rewritten paragraph.

The systems described herein may also be configured to focus light from the light sources to a plurality of spatially separated spots on the reticle. The system may be further configured to detect light transmitted or reflected from the plurality of spots. Such a system may be configured as described and illustrated in U.S. Patent Application Serial No. 09/636,129 entitled "Multiple Beam Inspection Apparatus and Method," by Kvamme et al., issued as U.S. Patent No. 6,636,301 to Kvamme et al., which is incorporated by reference as if fully set forth herein. The systems described herein may be further configured as illustrated and described by Kvamme et al.